



Sheet 1 of 1

FORM PTO-1449
(Rev. 7-80)

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

Atty. Docket No. 14641

Serial No.
10/797,607

LIST OF PRIOR ART CITED BY APPLICANT
(Use several sheets if necessary)

APPLICANT Mandelis et al.

FILING DATE 3/11/2004

GROUP 2884

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB-CLASS	FILING DATE IF APPROPRIATE
OG	AA	5667300	9/16/1997	Mandelis et al.			
OG	AB	5302830	4/12/1994	Shivanandan			
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FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCL ASS	TRANSLATION
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OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)

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OG	AH		<p>"Non-contacting measurements of photocarrier lifetimes in bulk- and polycrystalline thin-film Si photoconductive devices by photothermal radiometry", Mandelis et al., J. Appl. Phys. Vol. 80 (9), Nov 1. 1996, pgs. 5332-5341.</p>																																																												
OG	AI		<p>"Relative sensitivity of photomodulated reflectance and photothermal infrared radiometry to thermal and carrier plasma waves in semiconductors", Salnick et al., J. Appl. Phys. Vol. 82 (4), Aug 15, 1997, pgs. 1853-1859.</p>																																																												
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